## Influence of nitrogen oxides and UV-radiation on metal oxide surfaces: XPS investigation

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Catalytic and photocatalytic processes of atmospheric trace gases on the surface of Fe- and Ti-oxide containing mineral dusts may play an important role in atmospheric chemistry. On TiO<sub>2</sub>, UV-radiation induced electron/hole pairs can directly or indirectly via photogenerated reactive oxygen species affect environmental processes through the redox chemistry of atmospheric gases, volatile organic compounds, H<sub>2</sub>O and O<sub>2</sub> [1,2,3]. Photoelectron spectroscopy provides a valuable tool to study adsorption of nitrogen oxide species and the effect of UV-radiation on metal oxide surfaces [4,5]. Here, we have employed near-ambient-pressure x-ray photoelectron spectroscopy for measurements of nitrogen oxide chemistry on well defined Fe- and Ti-oxide surfaces.

The photoelectron spectroscopy measurements were performed at the beamline 9.3.2 at the Advanced Light Source. Core-level metal cation, O and N XPS-transitions, as well as valence band regions were measured at elevated pressures of NOx,  $O_2$ ,  $O_3$  and  $H_2O$ . Phases of surface nitrite and nitrate formation were observed after exposure to NO an  $O_3$ . Furthermore, photochemical experiments were conducted on TiO<sub>2</sub> surfaces in situ by using a UV diode laser.

## References

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